



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehdi Vaez-Iravani et al.
Assignee: KLA-Tencor Corporation
Title: Sample Inspection System
Application No.: 10/627,402 Filing Date: July 24, 2003
Examiner: Not yet assigned Group Art Unit: 2877
Docket No.: TNCR.152US7 Conf. No.: 2861

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

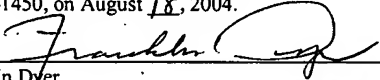
Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant calls the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

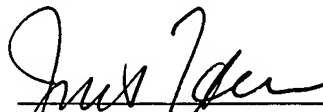
Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed, or were previously submitted in Application Nos. 10/033,069; 09/746,141; and 08/933,771, from which this Application claims an earlier effective filing date.

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

<p align="center"><u>Certificate of Mailing Under 37 CFR 1.8</u></p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope address to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on August <u>18</u>, 2004.</p> <p> _____ Franklin Dyer</p>

Respectfully submitted,



James S. Hsue
Reg. No. 29,545

8/18/04

Date

U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				TNCR.152US7		10/627,402	
				Applicant(s)		Conf. No.	
(Use several sheets if necessary)				M. Vaez-Iravani et al.		2861	
				Filing Date		Group	
				July 24, 2003		2877	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,558,949	12/85	Uehara et al.			
	AB	4,893,932	1/1990	Knollenberg			
	AC	5,058,982	10/1991	Katzir			
	AD	5,712,701	1/98	Dementi et al.			
	AE	5,929,983	7/99	Lu			
	AF	6,118,525	9/00	Fossey et al.			
	AG	6,169,601	1/01	Eremin et al.			

U.S. Published Patent Application Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AH	WO97/33158	9/1997	International			X	
	AI	EP0624787	11/1994	Europe			Abstract	
	AJ	DE4123916	1/1992	German			Abstract	
	AK	WO97/12226	4/1997	International			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
AL	"Surface Inspection System for Estimation of Wafer," Y. Yatsugake et al., <i>Hitachi Electronics Engineering Technical Report</i> , Vol. 11, January 1996, pp. 21-26	
AM	Figure, Hitachi Electronics Engineering Co., Ltd., presented by Etsuro Morita of Mitsubishi Materials Silicon Corp. in a presentation entitled "Exploration of COP and COP Defect Crystal Originated 'Particles'." at the 6 th International Workshop on 300 Millimeter Wafers on 12/5/1996 in Makuhari, Japan	
AN	Partial European Search Report dated October 18, 2000	

Examiner	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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				July 24, 2003		2877	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,589,773	5/86	Ido et al.			
	AB	4,740,079	04/88	Koizumi et al.			
	AC	4,966,457	10/90	Hayano et al.			
	AD	5,125,741	6/92	Okada et al.			
	AE	5,189,481	2/93	Jann et al.			
	AF	5,245,403	9/93	Kato et al.			
	AG	5,465,145	11/95	Nakashige et al.			

U.S. Published Patent Application Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AH	WO96/15354	9/25/96	International			X	
	AI	WO97/04134	3/5/97	International			X	
	AJ	WO99/14575	3/99	International			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
AK	Search Report Corresponding to PCT Application No. PCT/US98/19564 issued by the International Patent Office on February 8, 1999.

Examiner	Date Considered
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